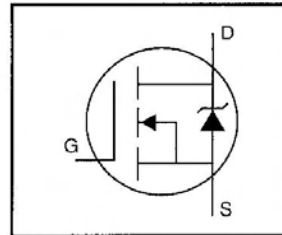


# IRFPE30PbF

HEXFET® Power MOSFET

- Dynamic dv/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements



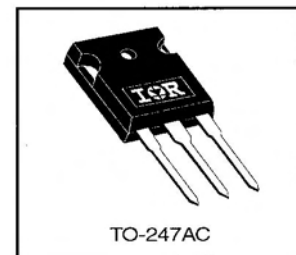
$V_{DSS} = 800V$   
 $R_{DS(on)} = 3.0\Omega$   
 $I_D = 4.1A$

• Lead-Free

### Description

Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because of its isolated mounting hole. It also provides greater creepage distance between pins to meet the requirements of most safety specifications.



### Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10 V$	4.1	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10 V$	2.6	
$I_{DM}$	Pulsed Drain Current ①	16	
$P_D @ T_C = 25^\circ C$	Power Dissipation	125	W
	Linear Derating Factor	1.0	W/°C
$V_{GS}$	Gate-to-Source Voltage	±20	V
$E_{AS}$	Single Pulse Avalanche Energy ②	170	mJ
$I_{AR}$	Avalanche Current ①	4.1	A
$E_{AR}$	Repetitive Avalanche Energy ①	13	mJ
dv/dt	Peak Diode Recovery dv/dt ③	2.0	V/ns
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting Torque, 6-32 or M3 screw	10 lbf•in (1.1 N•m)	

### Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	---	---	1.0	°C/W
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	---	0.24	---	
$R_{\theta JA}$	Junction-to-Ambient	---	---	40	

# IRFPE30PbF

International  
Rectifier

## Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

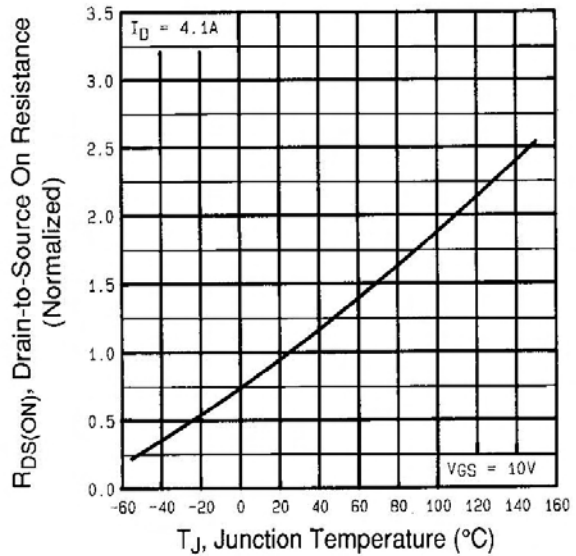
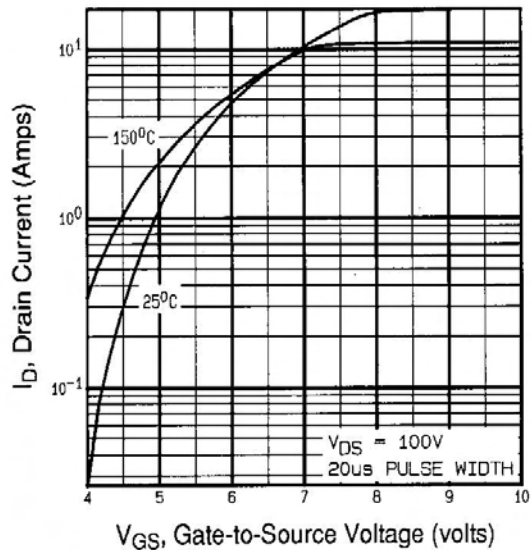
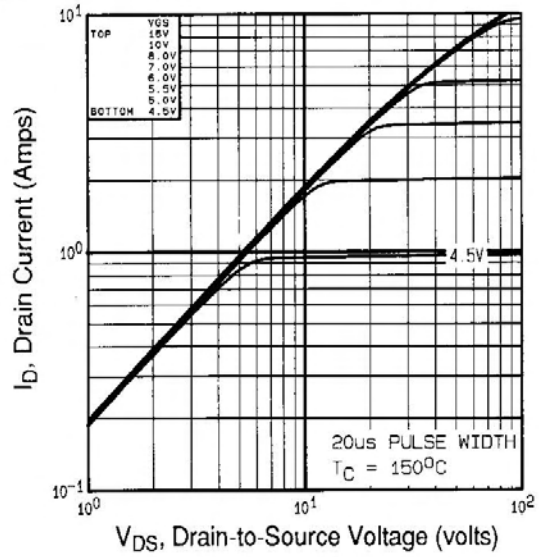
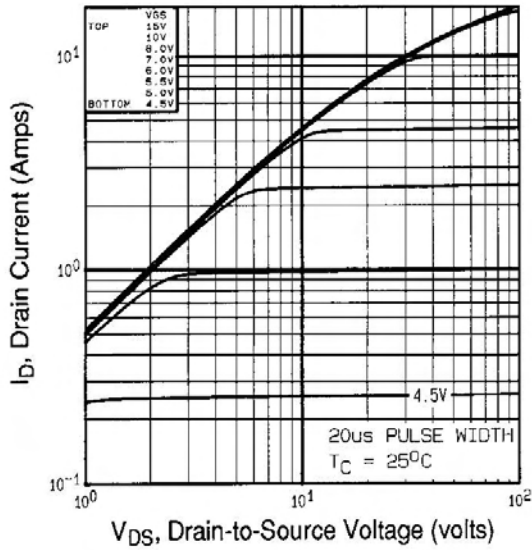
	Parameter	Min.	Typ.	Max.	Units	Test Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	800	—	—	V	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA
ΔV <sub>(BR)DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temp. Coefficient	—	0.90	—	V/°C	Reference to 25°C, I <sub>D</sub> =1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	—	—	3.0	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =2.5A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0	—	4.0	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA
g <sub>fs</sub>	Forward Transconductance	2.4	—	—	S	V <sub>DS</sub> =50V, I <sub>D</sub> =2.5A ④
I <sub>DSS</sub>	Drain-to-Source Leakage Current	—	—	100	μA	V <sub>DS</sub> =800V, V <sub>GS</sub> =0V
		—	—	500	μA	V <sub>DS</sub> =640V, V <sub>GS</sub> =0V, T <sub>J</sub> =125°C
I <sub>GSS</sub>	Gate-to-Source Forward Leakage	—	—	100	nA	V <sub>GS</sub> =20V
	Gate-to-Source Reverse Leakage	—	—	-100	nA	V <sub>GS</sub> =-20V
Q <sub>g</sub>	Total Gate Charge	—	—	78	nC	I <sub>D</sub> =4.1A
Q <sub>gs</sub>	Gate-to-Source Charge	—	—	9.6	nC	V <sub>DS</sub> =400V
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge	—	—	45	nC	V <sub>GS</sub> =10V See Fig. 6 and 13 ④
t <sub>d(on)</sub>	Turn-On Delay Time	—	12	—	ns	V <sub>DD</sub> =400V
t <sub>r</sub>	Rise Time	—	33	—	ns	I <sub>D</sub> =4.1A
t <sub>d(off)</sub>	Turn-Off Delay Time	—	82	—	ns	R <sub>G</sub> =12Ω
t <sub>f</sub>	Fall Time	—	30	—	ns	R <sub>D</sub> =95Ω See Figure 10 ④
L <sub>D</sub>	Internal Drain Inductance	—	5.0	—	nH	Between lead, 6 mm (0.25in.) from package and center of die contact
L <sub>S</sub>	Internal Source Inductance	—	13	—	nH	
C <sub>iss</sub>	Input Capacitance	—	1300	—	pF	V <sub>GS</sub> =0V
C <sub>oss</sub>	Output Capacitance	—	310	—	pF	V <sub>DS</sub> =25V
C <sub>rss</sub>	Reverse Transfer Capacitance	—	190	—	pF	f=1.0MHz See Figure 5

## Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	—	—	4.1	A	MOSFET symbol showing the integral reverse p-n junction diode.
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①	—	—	16	A	
V <sub>SD</sub>	Diode Forward Voltage	—	—	1.8	V	T <sub>J</sub> =25°C, I <sub>S</sub> =4.1A, V <sub>GS</sub> =0V ④
t <sub>rr</sub>	Reverse Recovery Time	—	480	720	ns	T <sub>J</sub> =25°C, I <sub>F</sub> =4.1A
Q <sub>rr</sub>	Reverse Recovery Charge	—	1.8	2.7	μC	di/dt=100A/μs ④
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )				

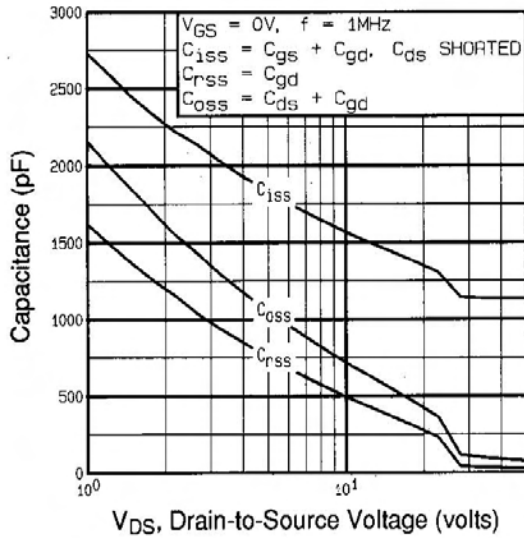
### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature (See Figure 11)
- ② V<sub>DD</sub>=50V, starting T<sub>J</sub>=25°C, L=18mH R<sub>G</sub>=25Ω, I<sub>AS</sub>=4.1A (See Figure 12)
- ③ I<sub>SD</sub>≤4.1A, di/dt≤100A/μs, V<sub>DD</sub>≤600, T<sub>J</sub>≤150°C
- ④ Pulse width ≤ 300 μs; duty cycle ≤2%.

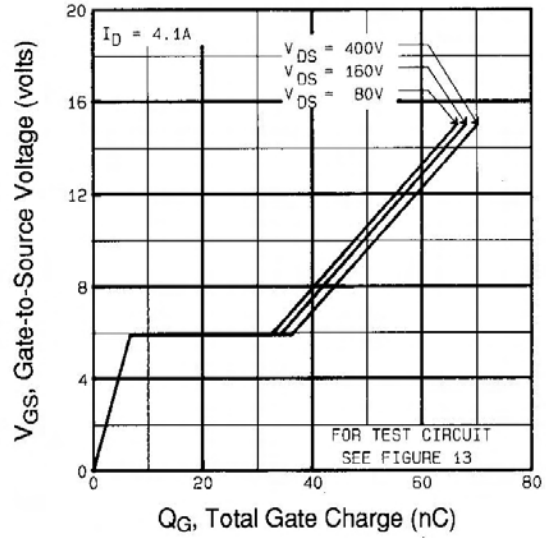


# IRFPE30PbF

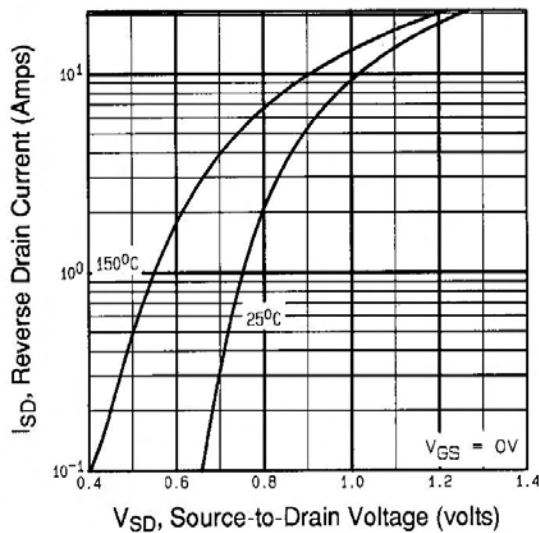
International  
**IR** Rectifier



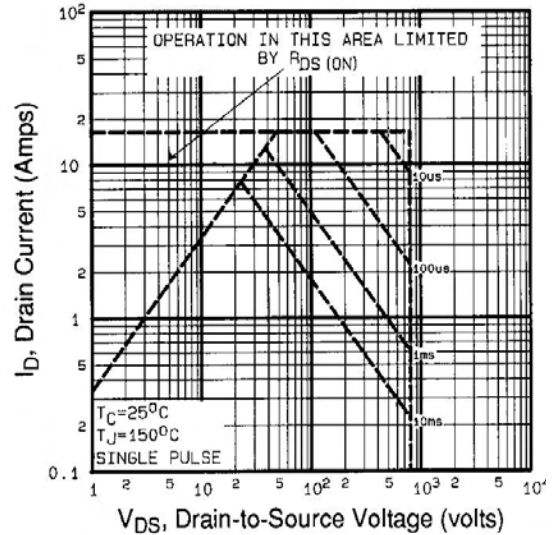
**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



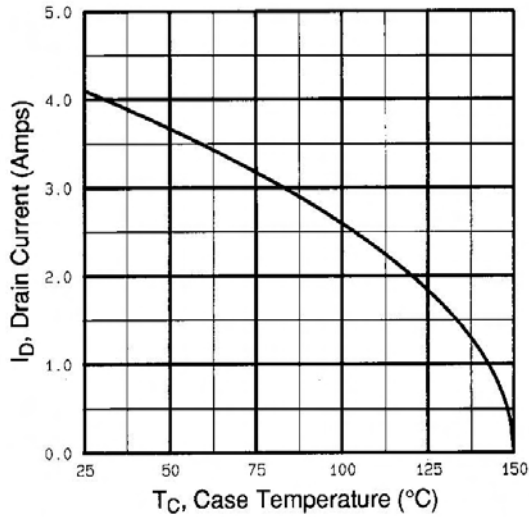
**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



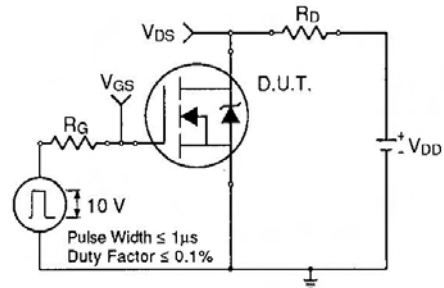
**Fig 7.** Typical Source-Drain Diode Forward Voltage



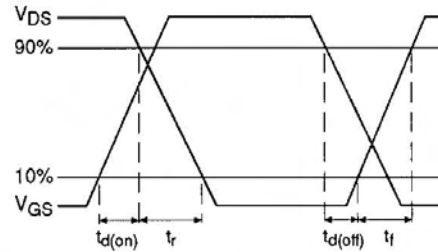
**Fig 8.** Maximum Safe Operating Area



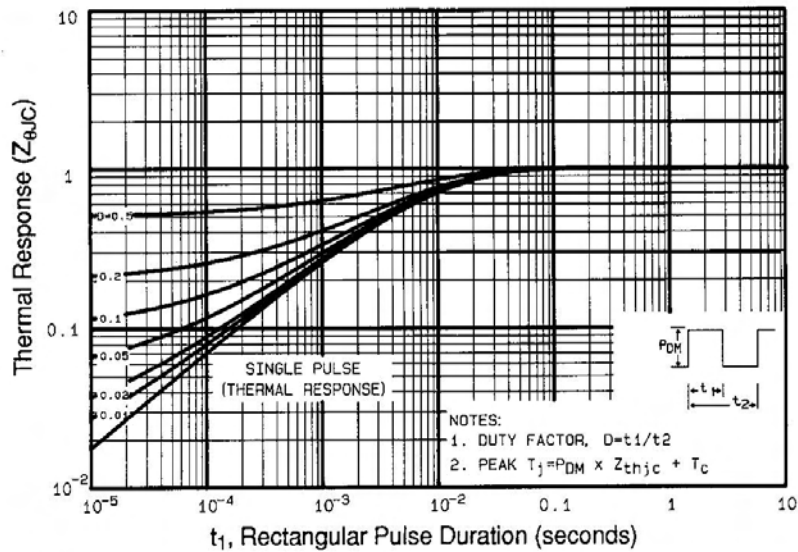
**Fig 9.** Maximum Drain Current Vs. Case Temperature



**Fig 10a.** Switching Time Test Circuit

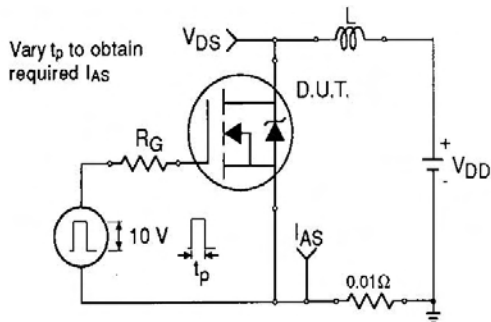


**Fig 10b.** Switching Time Waveforms

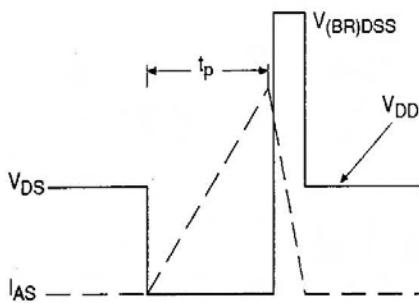


**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case

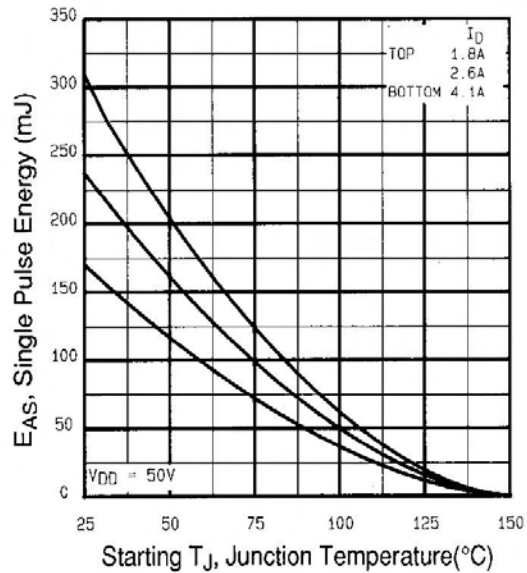
# IRFPE30PbF



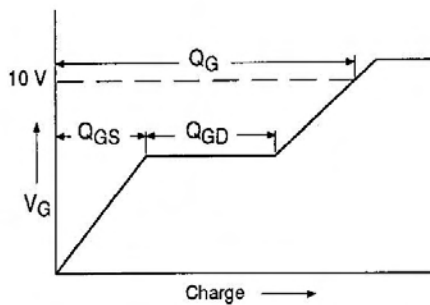
**Fig 12a.** Unclamped Inductive Test Circuit



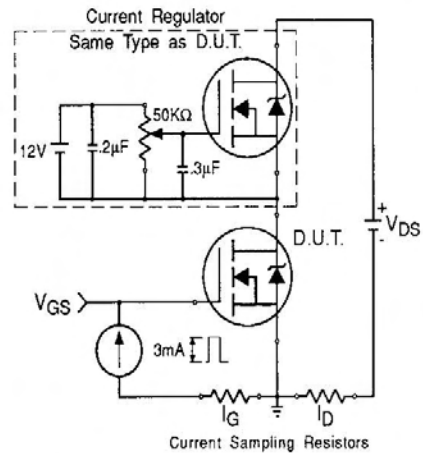
**Fig 12b.** Unclamped Inductive Waveforms



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current



**Fig 13a.** Basic Gate Charge Waveform



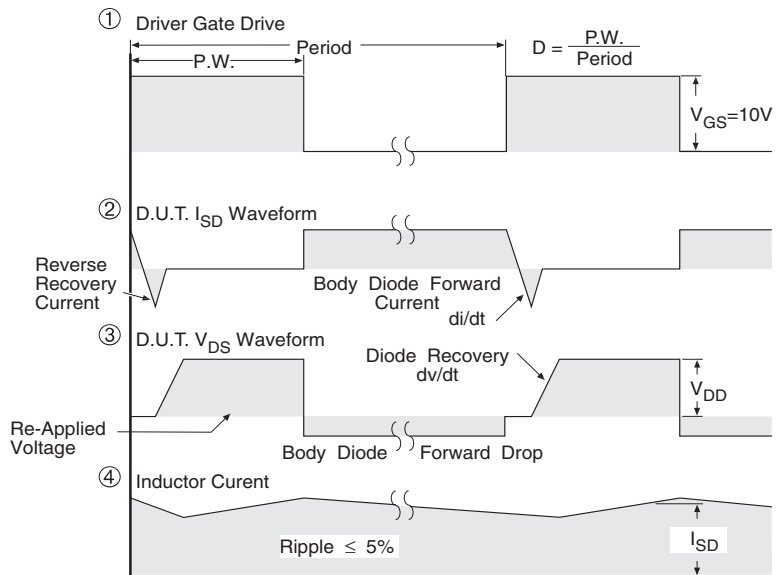
**Fig 13b.** Gate Charge Test Circuit

## Peak Diode Recovery dv/dt Test Circuit



\* Reverse Polarity for P-Channel

\*\* Use P-Channel Driver for P-Channel Measurements



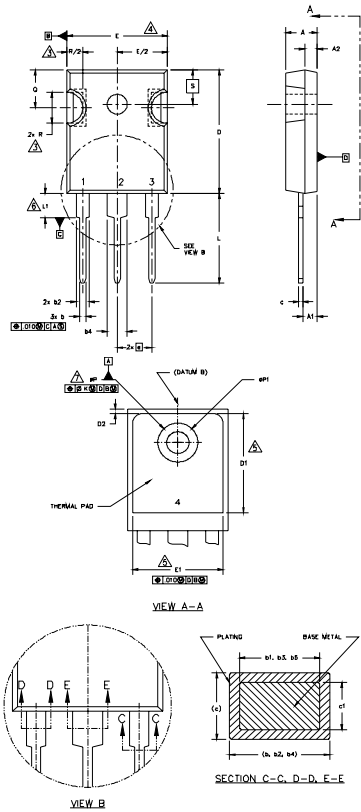
\*\*\*  $V_{GS} = 5.0V$  for Logic Level and 3V Drive Devices

**Fig -14 For N Channel HEXFETS**

# IRFPE30PbF



TO-247AC Package Outline Dimensions are shown in millimeters (inches)



NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M 1994.
2. DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS]
- CONTOUR OF SLOT OPTIONAL.
- DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS D1 & E1.
- LEAD FINISH UNCONTROLLED IN L1.
- ØP TO HAVE A MAXIMUM DRAFT ANGLE OF 1.5 ° TO THE TOP OF THE PART WITH A MAXIMUM HOLE DIAMETER OF .154" [3.91].
8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-247 WITH THE EXCEPTION OF DIMENSION c.

SYMBOL	DIMENSIONS				NOTES	LEAD ASSIGNMENTS
	INCHES		MILLIMETERS			
	MIN.	MAX.	MIN.	MAX.		
A	.183	.209	4.65	5.31		
A1	.087	.102	2.21	2.59		
A2	.059	.098	1.50	2.49		
b	.039	.055	0.99	1.40		
b1	.039	.055	0.99	1.35		1.- GATE
b2	.065	.094	1.65	2.39		2.- DRAIN
b3	.065	.092	1.65	2.37		3.- SOURCE
b4	.102	.135	2.59	3.45		4.- DRAIN
b5	.102	.133	2.59	3.38		
c	.015	.034	0.38	0.86		
c1	.015	.030	0.38	0.76		
D	.776	.815	19.71	20.70	4	
D1	.515	-	13.08	-	5	
D2	.020	.030	0.51	0.76		
E	.602	.625	15.29	15.87	4	
E1	.540	-	13.72	-		
e	.215 BSC		5.46 BSC			
Øk	.010		2.54			
L	.559	.634	14.20	16.10		
L1	.146	.169	3.71	4.29		
N	3		7.62 BSC			
ØP	.140	.144	3.56	3.66		
ØP1	-	.275	-	6.98		
Q	.209	.224	5.31	5.69		
R	.178	.216	4.52	5.49		
S	.217 BSC		5.51 BSC			

LEAD ASSIGNMENTS

HEXFET

1.- GATE  
2.- DRAIN  
3.- SOURCE  
4.- DRAIN

IGBTs, CoPACK

1.- GATE  
2.- COLLECTOR  
3.- EMITTER  
4.- COLLECTOR

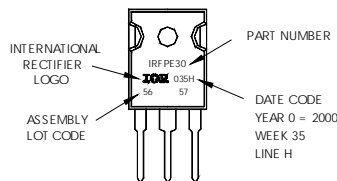
DIODES

1.- ANODE/OPEN  
2.- CATHODE  
3.- ANODE

## TO-247AC Part Marking Information

EXAMPLE: THIS IS AN IRFPE30 WITH ASSEMBLY LOT CODE 5657 ASSEMBLED ON WW 35, 2000 IN THE ASSEMBLY LINE "H"

Note: "P" in assembly line position indicates "Lead-Free"



Data and specifications subject to change without notice.



IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105  
TAC Fax: (310) 252-7903  
08/04





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